	σ	1	PT	P	D	ocument ID	Issue I	Date	Pages
1	⊠				US A1	20020089332	2002071	1	9
2	⊠				US	5825035 A	1998102	0	58
3	☒				us	5583344 A	1996121	0	43
4	☒				US	5504340 A	1996040	2	45
5	⊠				US	5426299 A	1995062	0	9
6	⊠				us	5223711 A	1993062	9	8
7	⊠				US	5185523 A	1993020	9	8
8	⊠				US	4714891 A	1987122	2	32
9	⊠				US A	20030049937	2003031	.2	12
10	×				EP	960431 B	1998082	:0	1
11	×				JР	06101040 A	1994041	.2	5

	Title	Current OR	Current XRef
1	Probe assembly for detecting an ion in a plasma generated in an ion source	324/466	
2	Processing method and apparatus using focused ion beam generating means	250/423R	250/492.21; 315/111.41; 315/111.81
3	generating means	250/492.21	250/423R
4	Process method and apparatus using focused ion beam generating means	250/492.21	250/309; 250/423R
5	Inductive plasma mass spectrometer	250/281	250/283; 250/286; 250/299; 250/300; 250/397
6	Plasma sources mass spectrometry	250/281	250/282; 250/283; 250/397
7	Mass spectrometer for analyzing ultra trace element using plasma ion source	250/281	250/282; 250/288
8	Method and apparatus for improving the safety and extending the range of ionization gauge systems	324/459	307/326; 324/500; 361/42
9	Substrate surface treatment apparatus for executing surface treatment to a substrate in a reaction chamber, comprises detecting device, and controller for controlling reduction of energy of ions in plasma	·	
10	Element selective detection - with a micro plasma mass spectrometer having a plasma ion source in the high vacuum chamber	·	
11	Ion implantation appts in which peak current density of ion beam is decreased by adjusting gap distance between ion source plasma chamber and drawing out pole		

	Retrieval Classif	Inventor	S	С	2	3	4	5
1		Benveniste, Victor M.						
2		Mizumura, Michinobu et al.						
3		Mizumura, Michinobu et al.						
4		Mizumura, Michinobu et al.						
5		Nakagawa, Yoshitomo et al.						
6		Sanderson, Neil E. et al.						
7		Kitagawa, Masatoshi et al.						
8		Morrison, Jr., Charles F.						
9		NISHIDA, K et al.						
10		BREDE, C et al.						
11								

	Image Doc. Displayed
1	US 20020089332
2	US 5825035
3	US 5583344
4	US 5504340
5	US 5426299
6	US 5223711
7	US 5185523
8	US 4714891
9	US 20030049937
10	EP 960431 A0
11	JP 06101040 A

	ט	1	PT	P	Document ID	Issue Date	Pages
12					WO 9102376 A	19910221	8

	Title	Current OR	Current XRef
12	Plasma source mass spectrometer - has inductively or microwave coupled source and mass filter and low collector shielded from neutral particles		

	Retrieval Classif	Inventor	S	С	2	3	4	5
12		SANDERSON, N E et al.						

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12	US 5223711

	Туре	L #	Hits	Search Text	DBs	Time Stamp
1	BRS	L1	12	(plasma adj10 chamber)	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2003/10/14 10:55